

Sten Bergstrand<sup>1</sup>, Andrew Yacoot<sup>2</sup>, Janet Miles<sup>3,4</sup>, Richard Davis<sup>5</sup>  
<sup>1</sup>RISE o/b/o BIPM, Editor-in-Chief *Metrologia*; <sup>2</sup>NPL, Editor-in-Chief *Measurement Science and Technology*; <sup>3,4</sup>BIPM/BIML, Editor *Metrologia*; <sup>5</sup>BIPM (ret.), Board Member *Metrologia*

<sup>1</sup>RISE o/b/o BIPM, Editor-in-Chief *Metrologia*; <sup>2</sup>NPL, Editor-in-Chief *Measurement Science and Technology*; <sup>3,4</sup>BIPM/BIML, Editor *Metrologia*; <sup>5</sup>BIPM (ret.), Board Member *Metrologia*

| Appendix table 1 | Diagram 1 | Diagram 2 | Diagram 3 | Diagram 4 | Diagram 5 | Diagram 6 |
|------------------|-----------|-----------|-----------|-----------|-----------|-----------|
|------------------|-----------|-----------|-----------|-----------|-----------|-----------|



**Together the journals cover the whole measurement chain  
from realisation of the SI to wider dissemination and application**

**<sup>2</sup>National Physical Laboratory, UK**  
**mst@ioppublishing.org**

**K IOP Publishing**